

E ffect of Iodine D oping on  $\text{Bi}_2\text{Sr}_2\text{Ca}_1\text{Cu}_2\text{O}_x$ :  
C harge T ransfer or Interlayer C oupling?

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A bstract

A com parative study has been m ade of iodine-intercalated  $\text{Bi}_2\text{Sr}_2\text{Ca}_1\text{Cu}_2\text{O}_x$  single crystal and 1 atm  $\text{O}_2$  annealed  $\text{Bi}_2\text{Sr}_2\text{Ca}_1\text{Cu}_1\text{O}_x$  single crystal using AC susceptibility m easurement, X-ray photoem ission (XPS) and angle-resolved ultraviolet photoem ission spectroscopy (ARUPS). AC susceptibility m easurement indicates that  $\text{O}_2$ -doped sam ples studied have  $T_c$  of 84 °K, whereas  $T_c$  of Iodine-doped sam ples studied are 80 °K. XPS Cu 2p core level data establish that the hole concentration in the  $\text{CuO}_2$  planes are essentially the sam e for these two kinds of sam ples. ARUPS m easurem ents show that electronic structure of the norm al states near the Ferm i level has been strongly a fected by iodine intercalation. W e conclude that the dom inant e ffect of iodine doping is to alter the interlayer coupling.

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The normal state properties of high  $T_c$  cuprate superconductors continues to be of much interest since probing the nature of the normal state may provide the key to understanding the mechanism of high- $T_c$  superconductivity. [1] Since the report that iodine has been successfully intercalated between BiO bilayers of the  $\text{Bi}_2\text{Sr}_2\text{Ca}_1\text{Cu}_2\text{O}_x$ , [2] many studies have been made of its crystal structure, [2,4,6,7] transport properties [3,5,8,11] and electronic properties. [10,12] A key unanswered question is how iodine intercalation alters the superconducting properties of intercalated  $\text{Bi}_2\text{Sr}_2\text{Ca}_1\text{Cu}_2\text{O}_x$ . By using transmission electron microscopy (TEM) and X-ray diffraction, Xiang et al [3,8] concluded that iodine is epitaxially intercalated between the BiO bilayers with  $\text{CuO}_2$  planes unaffected. They found that metallic  $\text{CuO}_2$  planes in the normal state above  $T_c$  are unaffected by the intercalation; however, the c-axis electrical resistivity is changed from semiconducting to metallic-like behavior. They attributed the reduction of  $T_c$  for  $\text{Bi}_2\text{Sr}_2\text{Ca}_1\text{Cu}_2\text{O}_x$  to the change of interlayer coupling, but did not rule out a smaller effect on  $T_c$  due to charge transfer from the iodine layers to the  $\text{CuO}_2$  layers. By contrast, based on X-ray photoemission (XPS) and Hall coefficient measurements, Pooke et al [11] and Choy et al [12] concluded that the dominant cause of changes in  $T_c$  is charge transfer from the iodine to the  $\text{CuO}_2$  planes. Whether  $T_c$  is controlled by in-plane carrier density or by interlayer coupling has been an important issue for a long time in the high  $T_c$  superconductivity community. [13] Our approach is to perform a comprehensive and comparative study of iodine-intercalated Bi-2212 and 1 atm  $\text{O}_2$  annealed Bi-2212. We concluded that it is the change of interlayer coupling due to the iodine intercalation that dominates the change of  $T_c$  between the two kinds of samples that have been studied. Using synchrotron radiation angle-resolved photoemission, we found that the electronic structure along one of the main symmetry directions, specially  $\Gamma$ -X (corresponding to the Bi-O bond axis in real space), has been strongly affected by this change of interlayer coupling associated with iodine intercalation.

The stage one  $\text{Bi}_2\text{Sr}_2\text{Ca}_1\text{Cu}_2\text{O}_x$  samples were prepared using the method reported by Xiang et al. [2,3,8] The samples were characterized by X-ray diffraction, micro-probe (Cameca CAMEBAX SX-50) and resistivity measurements.

The AC susceptibility measurements were obtained using a Lakeshore 7000 series susceptometer/magnetometer. The temperature step size has been chosen so that the determination of  $T_c$  was accurate to 0.2 K.

The X-ray photoemission spectroscopy (XPS) measurements were performed in Lausanne Centre de Spectromicroscopie, Switzerland, using the SCIENTA ESCA-300 system which is equipped with a rotating anode AlK $\alpha$  radiation source, a seven-quartz-crystal monochromator and a concentric hemispherical analyser. The overall energy resolution of the system for this measurement was 340 meV. The chamber pressure during the measurement was  $2 \times 10^{-10}$  torr.

The angle-resolved ultraviolet photoemission measurements were conducted using the four meter normal incidence monochromator at the Synchrotron Radiation Center in Wisconsin, and a Vacuum Science Workshop hemispherical angle-resolved analyser which has an acceptance full angle of two degrees. The experiment was performed at room temperature. The energy resolution of 140 meV was determined by measuring the Fermi edge of a gold film. The nominal chamber pressure during the measurement was  $1.7 \times 10^{-10}$  torr.

In both XPS and ARUPS measurements, the samples were placed in a load lock chamber with a base pressure lower than  $5 \times 10^{-9}$  torr, transferred into the main chamber, and cleaved under an ultra-high vacuum of  $2 \times 10^{-10}$ . In this way we made certain that both iodine-doped samples and O<sub>2</sub> annealed samples retained their original stoichiometries.

We confirmed the sample orientation using low energy electron diffraction. Our measurements along  $-X$  in reciprocal space correspond to the Bi-O bond axis direction in real space, while the  $-M$  direction in reciprocal space corresponds to the Cu-O-Cu bond axis direction in real space.

In order to separate the effects of charge transfer and interlayer coupling, we carefully altered the oxygen stoichiometry so that the Cu<sup>+1</sup>/Cu<sup>+2</sup> ratio obtained from XPS data was the same for the two types of samples. By doing so, we intended to determine the effects of interlayer coupling, without differences in charge transfer complicating the interpretation.

Fig. 1 illustrates Cu 2p<sub>3/2</sub> XPS core-level spectra for the B-2212 single crystals with 1

atm  $O_2$  annealing at 650 °C for 16 hours (a) and with iodine intercalation (b). We used one atmosphere  $O_2$  annealing to obtain as closely as possible the same carrier density for samples with and without iodine intercalation. From the spectrum one can observe a main peak at about 933 eV corresponding to the well-screened core hole final state of the  $2p^5 3d^{10}L$ , where L indicates a hole on the ligand oxygen, and a weak broad satellite centered at about 945 eV corresponding to a poorly-screened final state of the  $2p^5 3d^9$  configuration. We deconvoluted the main peak into three components. The two lower binding energy components comprise the  $Cu^{+1}$ . The satellite and the rest of higher binding energy components comprise  $Cu^{+2}$ . [14,10] Using this, the ratio of  $Cu^{+1}/Cu^{+2}$  for two kinds of samples are found to be 0.87 ± 0.03 for I-doped sample and 0.92 ± 0.03 for  $O_2$  annealed sample. These ratios are the same within experimental accuracy. The data indicates the carrier density in  $CuO_2$  planes are the same for the I-doped sample and  $O_2$  annealed sample.

Fig. 2 illustrates the AC susceptibility of a Bi2212 single crystal after 16 hours 1 atm  $O_2$  annealing at 650 °C and that of Bi2212 single crystal after iodine intercalation. The onset  $T_c$  is 84 °K for  $O_2$  annealed sample and 80 °K for the iodine-intercalated sample. The  $T_c$  of our as-grown samples is 90 °K. It is clear that there is a difference of 4 °K in their transition temperatures for 1 atm  $O_2$  annealed sample and I-doped sample.

Bi  $5d_{3/2}$  and  $5d_{5/2}$  spectra for Bi-2212 with  $O_2$  annealing and with iodine intercalation are shown in Fig. 3. We determined that the Bi  $5d_{3/2}$  and Bi  $5d_{5/2}$  levels have the same binding energies, 28.7 eV and 25.7 eV, respectively for the two kinds of samples. These results are consistent with Cu  $2p_{3/2}$  data, because we would expect no shift of corresponding core level binding energies since there is no difference in hole doping.

The above XPS Cu(2p) core level spectra, AC susceptibility data, Bi(5d) core level spectra establish that the difference in  $T_c$  between the two types of samples studied cannot be explained in terms of differences in hole concentration.

Xiang et al [8] interpreted the observed change in  $T_c$  using two models: the Wheatley-Hsu-Anderson (WHA) model [15] and, as they modified in Ref.9, the Ihm-Yu model [16]. They found that the depression of  $T_c$  can be understood if one assumes that the next-nearest

$\text{CuO}_2$  plane coupling is essentially eliminated by iodine intercalation; therefore, the interlayer hopping matrix element for the next-nearest-neighbor  $\text{CuO}_2$  planes is greatly reduced. Such an interpretation is consistent with high pressure experiments that report  $dT_c/dP > 0$ . [17] We studied whether there was any indication of change of interlayer coupling from the point of view of electronic structure. Specifically, we measured the band structure. The spectra illustrated in Fig. 4 were taken along the  $-X$  direction using a photon energy of 21 eV. For the iodine-intercalated sample Fig. 4, we observe a band dispersing towards the Fermi level from 160 meV below  $E_f$  at  $\theta$  of 10 degrees. The band crosses the Fermi level at  $\theta = 16$  degree and remains at the Fermi level for another two degrees. After crossing the Fermi level, the trailing edge of this band is still visible for  $\theta$  as large as 22 degrees. By contrast, for an oxygen annealed sample, the band crosses the Fermi level at  $\theta = 12$  degree. [18,19] The experimental dispersion relations for both iodine doped and  $\text{O}_2$  annealed samples are shown in Fig. 5. The amount of dispersion is quite different for two types of samples. The iodine intercalated samples exhibit a reduced dispersion, which is about 1.7 times less than that of the oxygen annealed sample, and a larger Fermi wave vector. Band structure calculations suggest that this band is mostly of  $\text{CuO}$  character. [20] The data indicate that the change of interlayer coupling has altered band structure in the  $-X$  direction.

We performed similar measurements in the  $-M$  direction. We found no significant difference in the dispersion or Fermi wave vector between samples.

In summary, our comparative study of iodine-intercalated Bi-2212 single crystal and  $\text{O}_2$  annealed Bi-2212 has found that the  $T_c$  is significantly affected by interlayer coupling effects rather than solely by hole carrier concentrations. Our data have established that the electronic structure of the normal state is dependent on the strength of the interlayer coupling.

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## FIGURES

FIG .1. The Cu ( $2p_{3/2}$ ) XPS core level spectra for iodine-intercalated Bi-2212 single crystal(a), and for 1 atm  $O_2$  annealed Bi-2212 (b).

FIG .2. The AC susceptibility data for iodine-intercalated Bi-2212 single crystal(a) and the data for 1 atm  $O_2$  annealed Bi-2212 (b). The onset  $T_c$ 's are 80 °K and 84 °K , respectively.

FIG .3. The Bi(5d) UPS core level spectra for iodine-intercalated Bi-2212 single crystal(a), and for 1 atm  $O_2$  annealed Bi-2212 (b).

FIG .4. The angle-resolved photoemission spectra of iodine-intercalated Bi-2212 taken at room temperature along the  $-X$  directions. The photon energy  $h\nu$  is 21 eV .

FIG .5. The dispersion relations of the same band along  $-X$  for iodine-intercalated Bi-2212 (a), and for 1 atm  $O_2$  annealed Bi-2212 (b). Both curves are experimental ones.